

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/522,591	KAYAMA ET AL.	
Examiner	Art Unit	
Oh annul. Fatramaslu.	2004	

SEARCHED						
Class	Subclass	Date	Examiner			
475	330	12/31/2007	SLE			
475	313	1/3/2008	SLE			
	319	1/3/2008	SLE			
	325	1/3/2008	SLE			
	269	1/3/2008	SLE			
	296	1/3/2008	SLE			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
475	313,319,	1/3/2008	SLE		
	325,330	1/3/2008	SLE		
	269,296	1/3/2008	SLE		

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